## JEOL TEM2010

The JEM-2010 (1994) is configured with LaB6 filament, equipped with STEM, EDS, 2kx2k GIF CCD (installed 2009) and Gatan GIF imaging filter (hardware upgrade 2009).

The 2010 is a general easy accessible instrument for conventional bright field/dark field imaging, HREM, basic analytical microscopy and diffraction studies. It is mostly used for metallurgic studies and nanotechnology.

Located in Materials Science building, Alfreds Getsvei, EM-Lab, F-361.



 $Lagret\ under: Server:\\ \\ | Elektronmikroskop\\ \\ | Lab\\ \\ | EOL\\ \\ | TEM\\ \\ |$